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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	324
Number of Logic Elements/Cells	1296
Total RAM Bits	-
Number of I/O	117
Number of Gates	16000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc5210-6tq144c

non-zero hold, attach a NODELAY attribute or property to the flip-flop or input buffer.

IOB Output Signals

Output signals can be optionally inverted within the IOB, and pass directly to the pad. As with the inputs, a CLB flip-flop or latch can be used to store the output signal.

An active-High 3-state signal can be used to place the output buffer in a high-impedance state, implementing 3-state outputs or bidirectional I/O. Under configuration control, the output (OUT) and output 3-state (T) signals can be inverted. The polarity of these signals is independently configured for each IOB.

The XC5200 devices provide a guaranteed output sink current of 8 mA.

Supported destinations for XC5200-Series device outputs are shown in Table 6.(For a detailed discussion of how to interface between 5 V and 3.3 V devices, see the 3V Products section of *The Programmable Logic Data Book*.)

An output can be configured as open-drain (open-collector) by placing an OBUFT symbol in a schematic or HDL code, then tying the 3-state pin (T) to the output signal, and the input pin (I) to Ground. (See Figure 12.)

Table 6: Supported Destinations for XC5200-Series Outputs

Destination	XC5200 Output Mode
	5 V, CMOS
XC5200 device, V_{CC}=3.3 V, CMOS-threshold inputs	√
Any typical device, V_{CC} = 3.3 V, CMOS-threshold inputs	some[1]
Any device, V_{CC} = 5 V, TTL-threshold inputs	√
Any device, V_{CC} = 5 V, CMOS-threshold inputs	√

1. Only if destination device has 5-V tolerant inputs

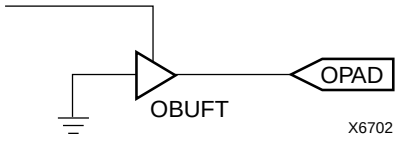


Figure 12: Open-Drain Output

Output Slew Rate

The slew rate of each output buffer is, by default, reduced, to minimize power bus transients when switching non-critical signals. For critical signals, attach a FAST attribute or property to the output buffer or flip-flop.

For XC5200 devices, maximum total capacitive load for simultaneous fast mode switching in the same direction is 200 pF for all package pins between each Power/Ground pin pair. For some XC5200 devices, additional internal Power/Ground pin pairs are connected to special Power and Ground planes within the packages, to reduce ground bounce.

For slew-rate limited outputs this total is two times larger for each device type: 400 pF for XC5200 devices. This maximum capacitive load should not be exceeded, as it can result in ground bounce of greater than 1.5 V amplitude and more than 5 ns duration. This level of ground bounce may cause undesired transient behavior on an output, or in the internal logic. This restriction is common to all high-speed digital ICs, and is not particular to Xilinx or the XC5200 Series.

XC5200-Series devices have a feature called “Soft Start-up,” designed to reduce ground bounce when all outputs are turned on simultaneously at the end of configuration. When the configuration process is finished and the device starts up, the first activation of the outputs is automatically slew-rate limited. Immediately following the initial activation of the I/O, the slew rate of the individual outputs is determined by the individual configuration option for each IOB.

Global Three-State

A separate Global 3-State line (not shown in Figure 11) forces all FPGA outputs to the high-impedance state, unless boundary scan is enabled and is executing an EXTEST instruction. This global net (GTS) does not compete with other routing resources; it uses a dedicated distribution network.

GTS can be driven from any user-programmable pin as a global 3-state input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GTS pin of the STARTUP symbol. A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global 3-State signal. Using GTS is similar to Global Reset. See Figure 8 on page 90 for details. Alternatively, GTS can be driven from any internal node.

Other IOB Options

There are a number of other programmable options in the XC5200-Series IOB.

Pull-up and Pull-down Resistors

Programmable IOB pull-up and pull-down resistors are useful for tying unused pins to Vcc or Ground to minimize power consumption and reduce noise sensitivity. The configurable pull-up resistor is a p-channel transistor that pulls

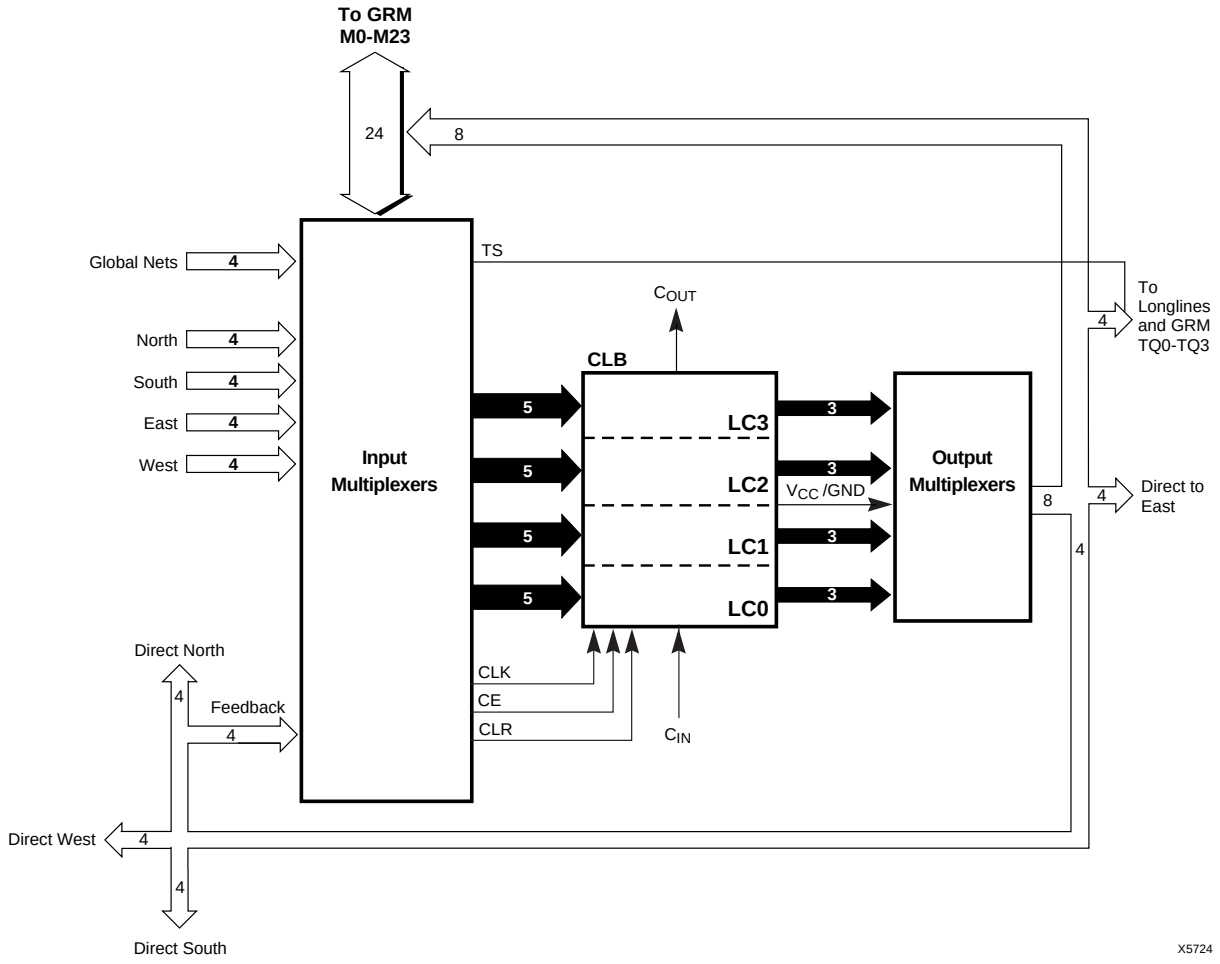


Figure 14: VersaBlock Details

CLB inputs have several possible sources: the 24 signals from the GRM, 16 direct connections from neighboring VersaBlocks, four signals from global, low-skew buffers, and the four signals from the CLB output multiplexers. Unlike the output multiplexers, the input multiplexers are not fully populated; i.e., only a subset of the available signals can be connected to a given CLB input. The flexibility of LUT input swapping and LUT mapping compensates for this limitation. For example, if a 2-input NAND gate is required, it can be mapped into any of the four LUTs, and use any two of the four inputs to the LUT.

Direct Connects

The unidirectional direct-connect segments are connected to the logic input/output pins through the CLB input and output multiplexer arrays, and thus bypass the general routing matrix altogether. These lines increase the routing channel utilization, while simultaneously reducing the delay incurred in speed-critical connections.

The direct connects also provide a high-speed path from the edge CLBs to the VersaRing input/output buffers, and thus reduce pin-to-pin set-up time, clock-to-out, and combinational propagation delay. Direct connects from the input buffers to the CLB DI pin (direct flip-flop input) are only available on the left and right edges of the device. CLB look-up table inputs and combinatorial/registered outputs have direct connects to input/output buffers on all four sides.

The direct connects are ideal for developing customized RPM cells. Using direct connects improves the macro performance, and leaves the other routing channels intact for improved routing. Direct connects can also route through a CLB using one of the four cell-feedthrough paths.

General Routing Matrix

The General Routing Matrix, shown in Figure 15, provides flexible bidirectional connections to the Local Interconnect

VersaRing Input/Output Interface

The VersaRing, shown in Figure 18, is positioned between the core logic and the pad ring; it has all the routing resources of a VersaBlock without the CLB logic. The VersaRing decouples the core logic from the I/O pads. Each VersaRing Cell provides up to four pad-cell connections on one side, and connects directly to the CLB ports on the other side.

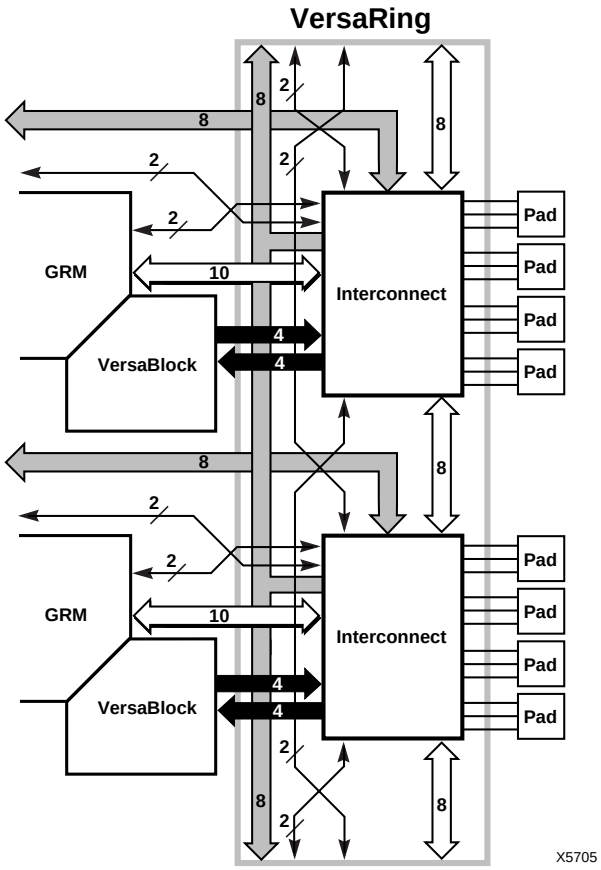


Figure 18: VersaRing I/O Interface

Boundary Scan

The “bed of nails” has been the traditional method of testing electronic assemblies. This approach has become less appropriate, due to closer pin spacing and more sophisticated assembly methods like surface-mount technology and multi-layer boards. The IEEE boundary scan standard 1149.1 was developed to facilitate board-level testing of electronic assemblies. Design and test engineers can imbed a standard test logic structure in their device to achieve high fault coverage for I/O and internal logic. This structure is easily implemented with a four-pin interface on any boundary scan-compatible IC. IEEE 1149.1-compatible devices may be serial daisy-chained together, connected in parallel, or a combination of the two.

XC5200 devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, SAMPLE/PRELOAD, and BYPASS instructions. The TAP can also support two USERCODE instructions. When the boundary scan configuration option is selected, three normal user I/O pins become dedicated inputs for these functions. Another user output pin becomes the dedicated boundary scan output.

Boundary-scan operation is independent of individual IOB configuration and package type. All IOBs are treated as independently controlled bidirectional pins, including any unbonded IOBs. Retaining the bidirectional test capability after configuration provides flexibility for interconnect testing.

Also, internal signals can be captured during EXTEST by connecting them to unbonded IOBs, or to the unused outputs in IOBs used as unidirectional input pins. This technique partially compensates for the lack of INTEST support.

The user can serially load commands and data into these devices to control the driving of their outputs and to examine their inputs. This method is an improvement over bed-of-nails testing. It avoids the need to over-drive device outputs, and it reduces the user interface to four pins. An optional fifth pin, a reset for the control logic, is described in the standard but is not implemented in Xilinx devices.

The dedicated on-chip logic implementing the IEEE 1149.1 functions includes a 16-state machine, an instruction register and a number of data registers. The functional details can be found in the IEEE 1149.1 specification and are also discussed in the Xilinx application note XAPP 017: *“Boundary Scan in XC4000 and XC5200 Series devices”*

Figure 19 on page 99 is a diagram of the XC5200-Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

The public boundary-scan instructions are always available prior to configuration. After configuration, the public instructions and any USERCODE instructions are only available if specified in the design. While SAMPLE and BYPASS are available during configuration, it is recommended that boundary-scan operations not be performed during this transitory period.

In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA device, and to read back the configuration data.

All of the XC4000 boundary-scan modes are supported in the XC5200 family. Three additional outputs for the User-Register are provided (Reset, Update, and Shift), repre-

XC5200-Series devices can also be configured through the boundary scan logic. See XAPP 017 for more information.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out and 3-State Control. Non-IOB pins have appropriate partial bit population for In or Out only. PROGRAM, CCLK and DONE are not included in the boundary scan register. Each EXTEST CAPTURE-DR state captures all In, Out, and 3-State pins.

The data register also includes the following non-pin bits: TDO.T, and TDO.O, which are always bits 0 and 1 of the data register, respectively, and BSCANT.UPD, which is always the last bit of the data register. These three boundary scan bits are special-purpose Xilinx test signals.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA provides two additional data registers that can be specified using the BSCAN macro. The FPGA provides two user pins (BSCAN.SEL1 and BSCAN.SEL2) which are the decodes of two user instructions, USER1 and USER2. For these instructions, two corresponding pins (BSCAN.TDO1 and BSCAN.TDO2) allow user scan data to be shifted out on TDO. The data register clock (BSCAN.DRCK) is available for control of test logic which the user may wish to implement with CLBs. The NAND of TCK and RUN-TEST-IDLE is also provided (BSCAN.IDLE).

Instruction Set

The XC5200-Series boundary scan instruction set also includes instructions to configure the device and read back the configuration data. The instruction set is coded as shown in Table 7.

Table 7: Boundary Scan Instructions

Instruction I2	I1	I0	Test Selected	TDO Source	I/O Data Source
0	0	0	EXTEST	DR	DR
0	0	1	SAMPLE/PRELOAD	DR	Pin/Logic
0	1	0	USER 1	BSCAN.TDO1	User Logic
0	1	1	USER 2	BSCAN.TDO2	User Logic
1	0	0	READBACK	Readback Data	Pin/Logic
1	0	1	CONFIGURE	DOUT	Disabled
1	1	0	Reserved	—	—
1	1	1	BYPASS	Bypass Register	—

Bit Sequence

The bit sequence within each IOB is: 3-State, Out, In. The data-register cells for the TAP pins TMS, TCK, and TDI have an OR-gate that permanently disables the output buffer if boundary-scan operation is selected. Consequently, it is impossible for the outputs in IOBs used by TAP inputs to conflict with TAP operation. TAP data is taken directly from the pin, and cannot be overwritten by injected boundary-scan data.

The primary global clock inputs (PGCK1-PGCK4) are taken directly from the pins, and cannot be overwritten with boundary-scan data. However, if necessary, it is possible to drive the clock input from boundary scan. The external clock source is 3-stated, and the clock net is driven with boundary scan data through the output driver in the clock-pad IOB. If the clock-pad IOBs are used for non-clock signals, the data may be overwritten normally.

Pull-up and pull-down resistors remain active during boundary scan. Before and during configuration, all pins are pulled up. After configuration, the choice of internal pull-up or pull-down resistor must be taken into account when designing test vectors to detect open-circuit PC traces.

From a cavity-up view of the chip (as shown in XDE or Epic), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Table 8. The device-specific pinout tables for the XC5200 Series include the boundary scan locations for each IOB pin.

Table 8: Boundary Scan Bit Sequence

Bit Position	I/O Pad Location
Bit 0 (TDO)	Top-edge I/O pads (right to left)
Bit 1	...
...	Left-edge I/O pads (top to bottom)
...	Bottom-edge I/O pads (left to right)
...	Right-edge I/O pads (bottom to top)
Bit N (TDI)	BSCANT.UPD

BSDL (Boundary Scan Description Language) files for XC5200-Series devices are available on the Xilinx web site in the File Download area.

Including Boundary Scan

If boundary scan is only to be used during configuration, no special elements need be included in the schematic or HDL code. In this case, the special boundary scan pins TDI, TMS, TCK and TDO can be used for user functions after configuration.

To indicate that boundary scan remain enabled after configuration, include the BSCAN library symbol and connect pad symbols to the TDI, TMS, TCK and TDO pins, as shown in Figure 20.

Table 9: Pin Descriptions (Continued)

Pin Name	I/O During Config.	I/O After Config.	Pin Description
TDI, TCK, TMS	I	I/O or I (JTAG)	If boundary scan is used, these pins are Test Data In, Test Clock, and Test Mode Select inputs respectively. They come directly from the pads, bypassing the IOBs. These pins can also be used as inputs to the CLB logic after configuration is completed. If the BSCAN symbol is not placed in the design, all boundary scan functions are inhibited once configuration is completed, and these pins become user-programmable I/O. In this case, they must be called out by special schematic definitions. To use these pins, place the library components TDI, TCK, and TMS instead of the usual pad symbols. Input or output buffers must still be used.
HDC	O	I/O	High During Configuration (HDC) is driven High until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, HDC is a user-programmable I/O pin.
$\overline{\text{LDC}}$	O	I/O	Low During Configuration ($\overline{\text{LDC}}$) is driven Low until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, $\overline{\text{LDC}}$ is a user-programmable I/O pin.
$\overline{\text{INIT}}$	I/O	I/O	Before and during configuration, $\overline{\text{INIT}}$ is a bidirectional signal. A 1 kΩ - 10 kΩ external pull-up resistor is recommended. As an active-Low open-drain output, $\overline{\text{INIT}}$ is held Low during the power stabilization and internal clearing of the configuration memory. As an active-Low input, it can be used to hold the FPGA in the internal WAIT state before the start of configuration. Master mode devices stay in a WAIT state an additional 50 to 250 µs after $\overline{\text{INIT}}$ has gone High. During configuration, a Low on this output indicates that a configuration data error has occurred. After the I/O go active, $\overline{\text{INIT}}$ is a user-programmable I/O pin.
GCK1 - GCK4	Weak Pull-up	I or I/O	Four Global inputs each drive a dedicated internal global net with short delay and minimal skew. These internal global nets can also be driven from internal logic. If not used to drive a global net, any of these pins is a user-programmable I/O pin. The GCK1-GCK4 pins provide the shortest path to the four Global Buffers. Any input pad symbol connected directly to the input of a BUFG symbol is automatically placed on one of these pins.
$\overline{\text{CS0}}$, $\overline{\text{CS1}}$, $\overline{\text{WS}}$, $\overline{\text{RS}}$	I	I/O	These four inputs are used in Asynchronous Peripheral mode. The chip is selected when $\overline{\text{CS0}}$ is Low and CS1 is High. While the chip is selected, a Low on Write Strobe ($\overline{\text{WS}}$) loads the data present on the D0 - D7 inputs into the internal data buffer. A Low on Read Strobe ($\overline{\text{RS}}$) changes D7 into a status output — High if Ready, Low if Busy — and drives D0 - D6 High. In Express mode, CS1 is used as a serial-enable signal for daisy-chaining. $\overline{\text{WS}}$ and $\overline{\text{RS}}$ should be mutually exclusive, but if both are Low simultaneously, the Write Strobe overrides. After configuration, these are user-programmable I/O pins.
A0 - A17	O	I/O	During Master Parallel configuration, these 18 output pins address the configuration EPROM. After configuration, they are user-programmable I/O pins.
D0 - D7	I	I/O	During Master Parallel, Peripheral, and Express configuration, these eight input pins receive configuration data. After configuration, they are user-programmable I/O pins.
DIN	I	I/O	During Slave Serial or Master Serial configuration, DIN is the serial configuration data input receiving data on the rising edge of CCLK. During Parallel configuration, DIN is the D0 input. After configuration, DIN is a user-programmable I/O pin.
DOUT	O	I/O	During configuration in any mode but Express mode, DOUT is the serial configuration data output that can drive the DIN of daisy-chained slave FPGAs. DOUT data changes on the falling edge of CCLK. In Express mode, DOUT is the status output that can drive the CS1 of daisy-chained FPGAs, to enable and disable downstream devices. After configuration, DOUT is a user-programmable I/O pin.

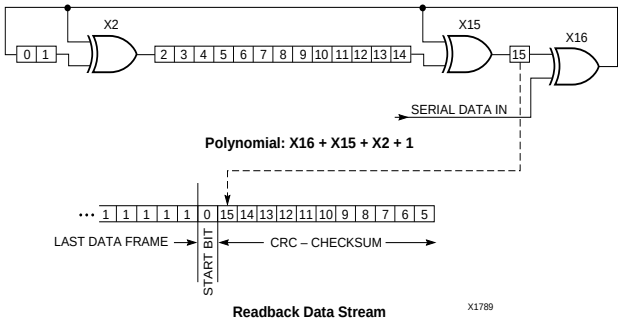


Figure 23: Circuit for Generating CRC-16

Configuration Sequence

There are four major steps in the XC5200-Series power-up configuration sequence.

- Power-On Time-Out
- Initialization
- Configuration
- Start-Up

The full process is illustrated in Figure 24.

Power-On Time-Out

An internal power-on reset circuit is triggered when power is applied. When V_{CC} reaches the voltage at which portions of the FPGA begin to operate (i.e., performs a write-and-read test of a sample pair of configuration memory bits), the programmable I/O buffers are 3-stated with active high-impedance pull-up resistors. A time-out delay — nominally 4 ms — is initiated to allow the power-supply voltage to stabilize. For correct operation the power supply must reach V_{CC}(min) by the end of the time-out, and must not dip below it thereafter.

There is no distinction between master and slave modes with regard to the time-out delay. Instead, the $\overline{\text{INIT}}$ line is used to ensure that all daisy-chained devices have completed initialization. Since XC2000 devices do not have this signal, extra care must be taken to guarantee proper operation when daisy-chaining them with XC5200 devices. For proper operation with XC3000 devices, the $\overline{\text{RESET}}$ signal, which is used in XC3000 to delay configuration, should be connected to $\overline{\text{INIT}}$.

If the time-out delay is insufficient, configuration should be delayed by holding the $\overline{\text{INIT}}$ pin Low until the power supply has reached operating levels.

This delay is applied only on power-up. It is not applied when reconfiguring an FPGA by pulsing the $\overline{\text{PROGRAM}}$ pin Low. During all three phases — Power-on, Initialization, and Configuration — DONE is held Low; HDC, $\overline{\text{LDC}}$, and $\overline{\text{INIT}}$ are active; DOUT is driven; and all I/O buffers are disabled.

Initialization

This phase clears the configuration memory and establishes the configuration mode.

The configuration memory is cleared at the rate of one frame per internal clock cycle (nominally 1 MHz). An open-drain bidirectional signal, $\overline{\text{INIT}}$, is released when the configuration memory is completely cleared. The device then tests for the absence of an external active-low level on $\overline{\text{INIT}}$. The mode lines are sampled two internal clock cycles later (nominally 2 µs).

The master device waits an additional 32 µs to 256 µs (nominally 64-128 µs) to provide adequate time for all of the slave devices to recognize the release of $\overline{\text{INIT}}$ as well. Then the master device enters the Configuration phase.

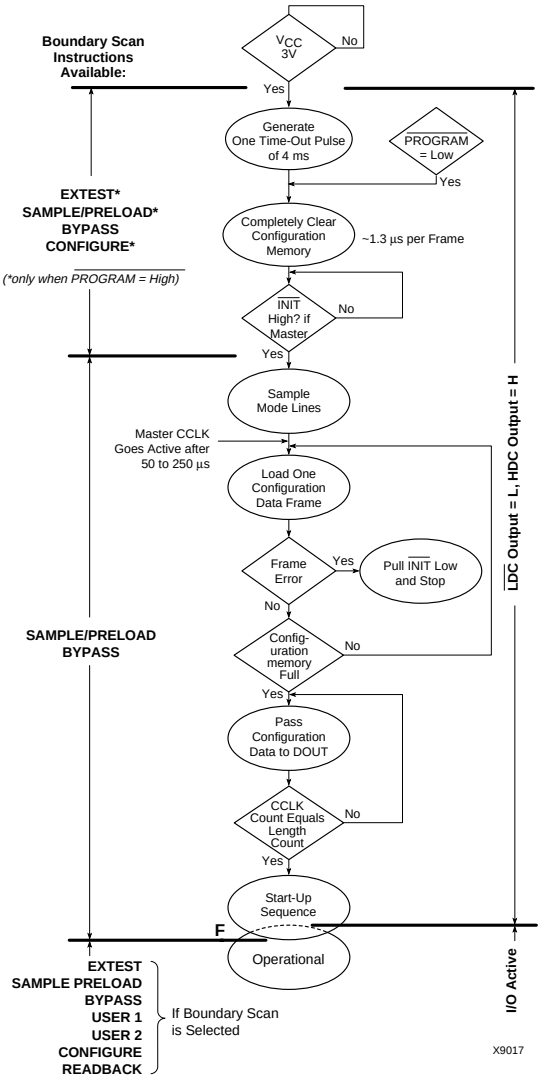


Figure 24: Configuration Sequence

Note that in XC5200-Series devices, configuration data is *not* inverted with respect to configuration as it is in XC2000 and XC3000 families.

Readback of Express mode bitstreams results in data that does not resemble the original bitstream, because the bitstream format differs from other modes.

XC5200-Series Readback does not use any dedicated pins, but uses four internal nets (RDBK.TRIG, RDBK.DATA, RDBK.RIP and RDBK.CLK) that can be routed to any IOB. To access the internal Readback signals, place the READBACK library symbol and attach the appropriate pad symbols, as shown in Figure 27.

After Readback has been initiated by a Low-to-High transition on RDBK.TRIG, the RDBK.RIP (Read In Progress) output goes High on the next rising edge of RDBK.CLK. Subsequent rising edges of this clock shift out Readback data on the RDBK.DATA net.

Readback data does not include the preamble, but starts with five dummy bits (all High) followed by the Start bit (Low) of the first frame. The first two data bits of the first frame are always High.

Each frame ends with four error check bits. They are read back as High. The last seven bits of the last frame are also read back as High. An additional Start bit (Low) and an 11-bit Cyclic Redundancy Check (CRC) signature follow, before RDBK.RIP returns Low.

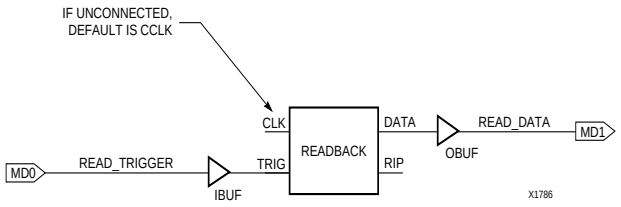


Figure 27: Readback Schematic Example

Readback Options

Readback options are: Read Capture, Read Abort, and Clock Select. They are set with the bitstream generation software.

Read Capture

When the Read Capture option is selected, the readback data stream includes sampled values of CLB and IOB signals. The rising edge of RDBK.TRIG latches the inverted values of the CLB outputs and the IOB output and input signals. Note that while the bits describing configuration (interconnect and function generators) are *not* inverted, the CLB and IOB output signals *are* inverted.

When the Read Capture option is not selected, the values of the capture bits reflect the configuration data originally written to those memory locations.

The readback signals are located in the lower-left corner of the device.

Read Abort

When the Read Abort option is selected, a High-to-Low transition on RDBK.TRIG terminates the readback operation and prepares the logic to accept another trigger.

After an aborted readback, additional clocks (up to one readback clock per configuration frame) may be required to re-initialize the control logic. The status of readback is indicated by the output control net RDBK.RIP. RDBK.RIP is High whenever a readback is in progress.

Clock Select

CCLK is the default clock. However, the user can insert another clock on RDBK.CLK. Readback control and data are clocked on rising edges of RDBK.CLK. If readback must be inhibited for security reasons, the readback control nets are simply not connected.

Violating the Maximum High and Low Time Specification for the Readback Clock

The readback clock has a maximum High and Low time specification. In some cases, this specification cannot be met. For example, if a processor is controlling readback, an interrupt may force it to stop in the middle of a readback. This necessitates stopping the clock, and thus violating the specification.

The specification is mandatory only on clocking data at the end of a frame prior to the next start bit. The transfer mechanism will load the data to a shift register during the last six clock cycles of the frame, prior to the start bit of the following frame. This loading process is dynamic, and is the source of the maximum High and Low time requirements.

Therefore, the specification only applies to the six clock cycles prior to and including any start bit, including the clocks before the first start bit in the readback data stream. At other times, the frame data is already in the register and the register is not dynamic. Thus, it can be shifted out just like a regular shift register.

The user must precisely calculate the location of the readback data relative to the frame. The system must keep track of the position within a data frame, and disable interrupts before frame boundaries. Frame lengths and data formats are listed in Table 11 and Table 12.

Readback with the XChecker Cable

The XChecker Universal Download/Readback Cable and Logic Probe uses the readback feature for bitstream verification. It can also display selected internal signals on the PC or workstation screen, functioning as a low-cost in-circuit emulator.

Configuration Timing

The seven configuration modes are discussed in detail in this section. Timing specifications are included.

Slave Serial Mode

In Slave Serial mode, an external signal drives the CCLK input of the FPGA. The serial configuration bitstream must be available at the DIN input of the lead FPGA a short setup time before each rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin.

There is an internal delay of 0.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

Figure 28 shows a full master/slave system. An XC5200-Series device in Slave Serial mode should be connected as shown in the third device from the left.

Slave Serial mode is selected by a <111> on the mode pins (M2, M1, M0). Slave Serial is the default mode if the mode pins are left unconnected, as they have weak pull-up resistors during configuration.

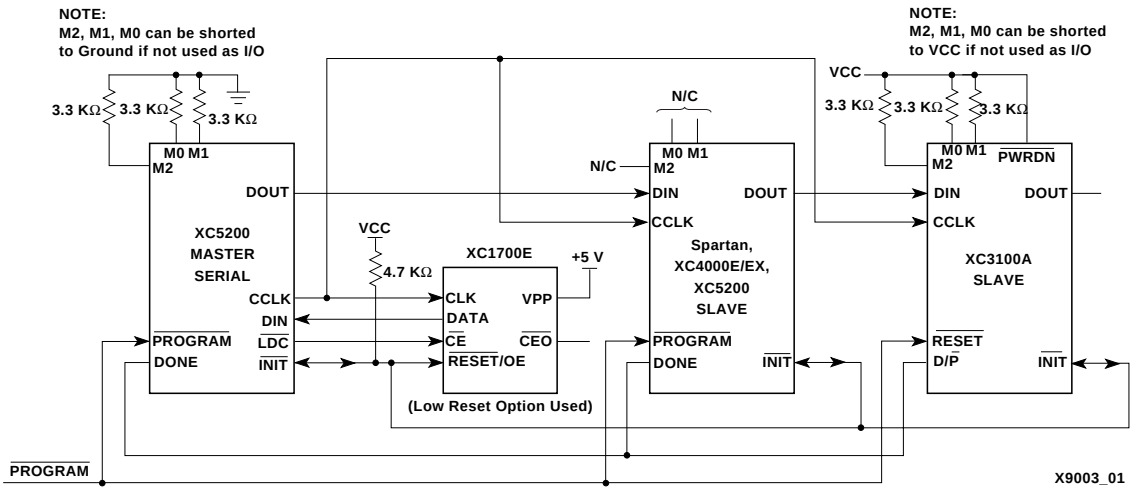
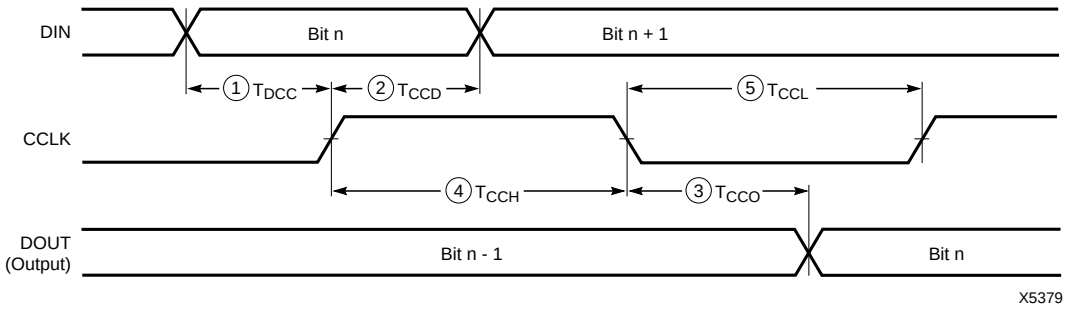


Figure 28: Master/Slave Serial Mode Circuit Diagram



	Description	Symbol		Min	Max	Units
CCLK	DIN setup	1	T_{DCC}	20		ns
	DIN hold	2	T_{CCD}	0		ns
	DIN to DOUT	3	T_{CCO}		30	ns
	High time	4	T_{CCH}	45		ns
	Low time	5	T_{CCL}	45		ns
	Frequency		F_{CC}		10	MHz

Note: Configuration must be delayed until the $\overline{INIT}$ pins of all daisy-chained FPGAs are High.

Figure 29: Slave Serial Mode Programming Switching Characteristics

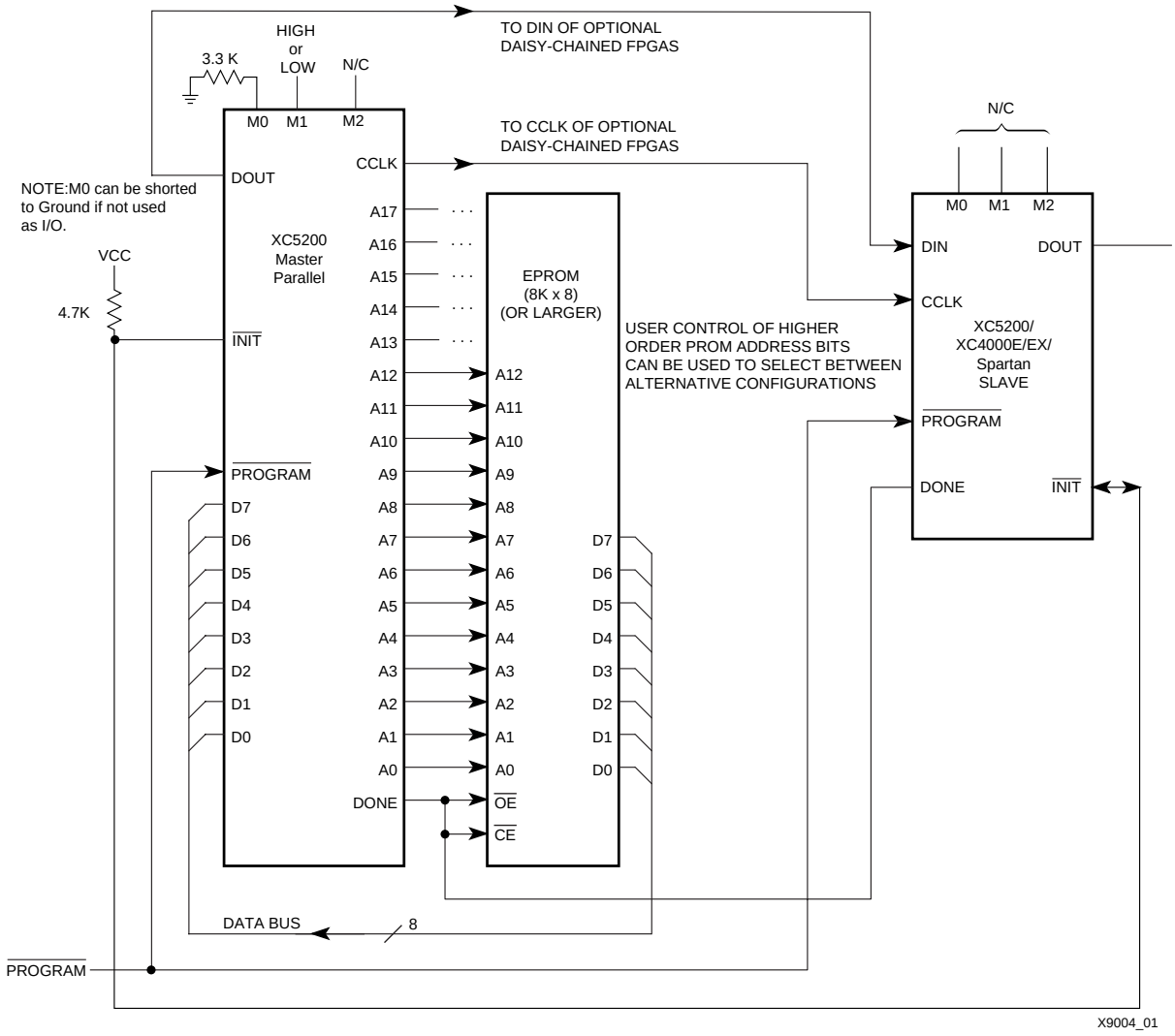
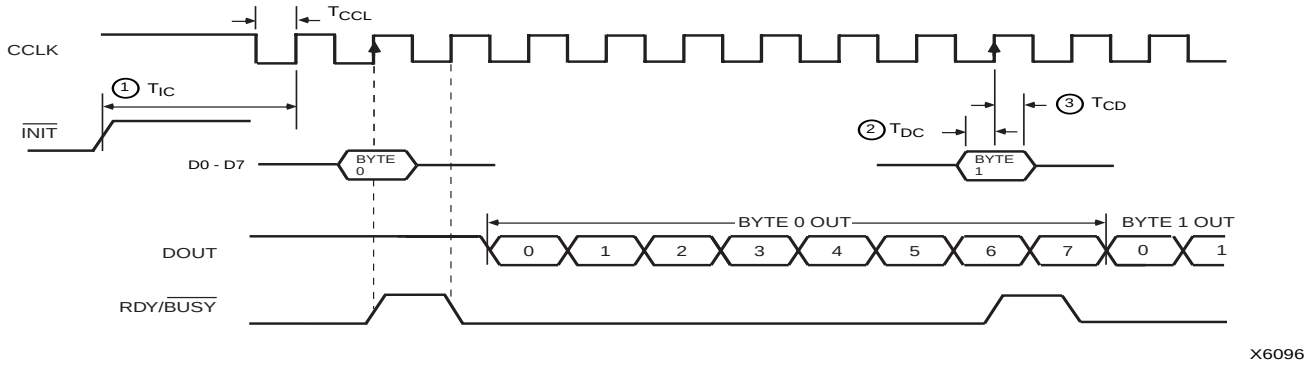


Figure 31: Master Parallel Mode Circuit Diagram



	Description	Symbol		Min	Max	Units
CCLK	INIT (High) setup time	1	T_{IC}	5		µs
	D0 - D7 setup time	2	T_{DC}	60		ns
	D0 - D7 hold time	3	T_{CD}	0		ns
	CCLK High time		T_{CCH}	50		ns
	CCLK Low time		T_{CCL}	60		ns
	CCLK Frequency		F_{CC}		8	MHz

Notes: 1. Peripheral Synchronous mode can be considered Slave Parallel mode. An external CCLK provides timing, clocking in the **first** data byte on the **second** rising edge of CCLK after INIT goes high. Subsequent data bytes are clocked in on every eighth consecutive rising edge of CCLK.
2. The RDY/BUSY line goes High for one CCLK period after data has been clocked in, although synchronous operation does not require such a response.
3. The pin name RDY/BUSY is a misnomer. In synchronous peripheral mode this is really an ACKNOWLEDGE signal.
4.Note that data starts to shift out serially on the DOUT pin 0.5 CCLK periods after it was loaded in parallel. Therefore, additional CCLK pulses are clearly required after the last byte has been loaded.

Figure 34: Synchronous Peripheral Mode Programming Switching Characteristics

Express Mode

Express mode is similar to Slave Serial mode, except that data is processed one byte per CCLK cycle instead of one bit per CCLK cycle. An external source is used to drive CCLK, while byte-wide data is loaded directly into the configuration data shift registers. A CCLK frequency of 10 MHz is equivalent to an 80 MHz serial rate, because eight bits of configuration data are loaded per CCLK cycle. Express mode does not support CRC error checking, but does support constant-field error checking.

In Express mode, an external signal drives the CCLK input of the FPGA device. The first byte of parallel configuration data must be available at the D inputs of the FPGA a short setup time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge.

If the first device is configured in Express mode, additional devices may be daisy-chained only if every device in the chain is also configured in Express mode. CCLK pins are tied together and D0-D7 pins are tied together for all devices along the chain. A status signal is passed from DOUT to CS1 of successive devices along the chain. The lead device in the chain has its CS1 input tied High (or floating, since there is an internal pullup). Frame data is accepted only when CS1 is High and the device's configuration memory is not already full. The status pin DOUT is pulled Low two internal-oscillator cycles after INIT is recognized as High, and remains Low until the device's configuration memory is full. DOUT is then pulled High to signal the next device in the chain to accept the configuration data on the D0-D7 bus.

The DONE pins of all devices in the chain should be tied together, with one or more active internal pull-ups. If a large number of devices are included in the chain, deactivate some of the internal pull-ups, since the Low-driving DONE pin of the last device in the chain must sink the current from all pull-ups in the chain. The DONE pull-up is activated by default. It can be deactivated using an option in the bitstream generation software.

XC5200 devices in Express mode are always synchronized to DONE. The device becomes active after DONE goes High. DONE is an open-drain output. With the DONE pins tied together, therefore, the external DONE signal stays low until all devices are configured, then all devices in the daisy chain become active simultaneously. If the DONE pin of a device is left unconnected, the device becomes active as soon as that device has been configured.

Express mode is selected by a <010> on the mode pins (M2, M1, M0).

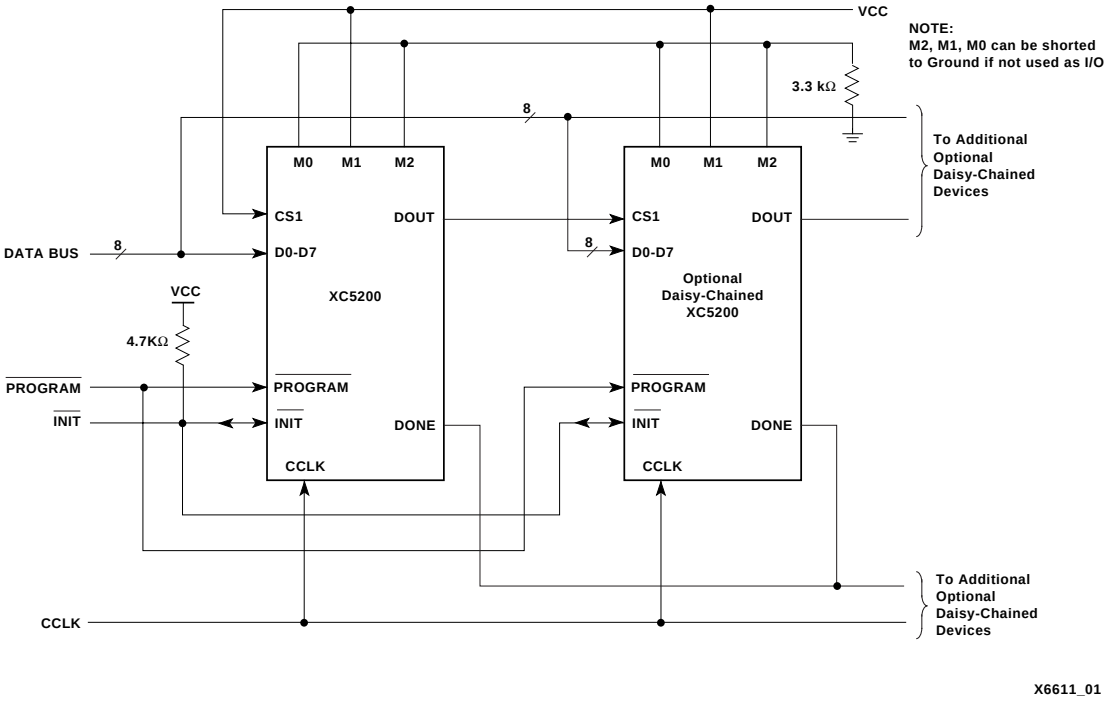


Figure 37: Express Mode Circuit Diagram

XC5200 IOB Switching Characteristic Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

Speed Grade		-6	-5	-4	-3
Description	**Symbol**	**Max (ns)**	**Max (ns)**	**Max (ns)**	**Max (ns)**
Input					
Propagation Delays from CMOS or TTL Levels					
Pad to I (no delay)	T_{PI}	5.7	5.0	4.8	3.3
Pad to I (with delay)	T_{PID}	11.4	10.2	10.2	9.5
Output					
Propagation Delays to CMOS or TTL Levels					
Output (O) to Pad (fast)	T_{OPF}	4.6	4.5	4.5	3.5
Output (O) to Pad (slew-limited)	T_{OPS}	9.5	8.4	8.0	5.0
From clock (CK) to output pad (fast), using direct connect between Q and output (O)	T_{OKPOF}	10.1	9.3	8.3	7.5
From clock (CK) to output pad (slew-limited), using direct connect between Q and output (O)	T_{OKPOS}	14.9	13.1	11.8	10.0
3-state to Pad active (fast)	T_{TSONF}	5.6	5.2	4.9	4.6
3-state to Pad active (slew-limited)	T_{TSONS}	10.4	9.0	8.3	6.0
Internal GTS to Pad active	T_{GTS}	17.7	15.9	14.7	13.5

Note:
1. Timing is measured at pin threshold, with 50-pF external capacitance loads. **Slew-limited** output rise/fall times are approximately two times longer than **fast** output rise/fall times.
2. Unused and unbonded IOBs are configured by default as inputs with internal pull-up resistors.
3. Timing is based upon the XC5215 device. For other devices, see Timing Calculator.

XC5200 Boundary Scan (JTAG) Switching Characteristic Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions. They are expressed in units of nanoseconds and apply to all XC5200 devices unless otherwise noted.

Speed Grade		-6		-5		-4		-3	
Description	**Symbol**	**Min**	**Max**	**Min**	**Max**	**Min**	**Max**	**Min**	**Max**
Setup and Hold									
Input (TDI) to clock (TCK) setup time	T_{TDITCK}	30.0		30.0		30.0		30.0	
Input (TDI) to clock (TCK) hold time	T_{TCKTDI}	0		0		0		0	
Input (TMS) to clock (TCK) setup time	T_{TMSTCK}	15.0		15.0		15.0		15.0	
Input (TMS) to clock (TCK) hold time	T_{TCKTMS}	0		0		0		0	
Propagation Delay									
Clock (TCK) to Pad (TDO)	T_{TCKPO}		30.0		30.0		30.0		30.0
Clock									
Clock (TCK) High	T_{TCKH}	30.0		30.0		30.0		30.0	
Clock (TCK) Low	T_{TCKL}	30.0		30.0		30.0		30.0	
F_{MAX} (MHz)	F_{MAX}		10.0		10.0		10.0		10.0

Note 1: Input pad setup and hold times are specified with respect to the internal clock.

Pin	Description		PC84	PQ100	VQ100	TQ144	PG156	PQ160	Boundary Scan Order
57.	I/O		-	-	-	47	E16	53	306
58.	I/O		38	34	31	48	F16	54	312
59.	I/O		39	35	32	49	G14	55	315
60.	I/O		-	36	33	50	G15	56	318
61.	I/O		-	37	34	51	G16	57	324
62.	I/O		40	38	35	52	H16	58	327
63.	I/O ($\overline{ERR}$, $\overline{INIT}$)		41	39	36	53	H15	59	330
	VCC		42	40	37	54	H14	60	-
	GND		43	41	38	55	J14	61	-
64.	I/O		44	42	39	56	J15	62	336
65.	I/O		45	43	40	57	J16	63	339
66.	I/O		-	44	41	58	K16	64	348
67.	I/O		-	45	42	59	K15	65	351
68.	I/O		46	46	43	60	K14	66	354
69.	I/O		47	47	44	61	L16	67	360
70.	I/O		-	-	-	62	M16	68	363
71.	I/O		-	-	-	63	L15	69	366
	GND		-	-	-	64	L14	70	-
72.	I/O		-	-	-	-	N16	71	372
73.	I/O		-	-	-	-	M15	72	375
74.	I/O		48	48	45	65	P16	73	378
75.	I/O		49	49	46	66	M14	74	384
76.	I/O		-	-	-	67	N15	75	387
77.	I/O		-	-	-	68	P15	76	390
78.	I/O		50	50	47	69	N14	77	396
79.	I/O		51	51	48	70	R16	78	399
	GND		52	52	49	71	P14	79	-
	DONE		53	53	50	72	R15	80	-
	VCC		54	54	51	73	P13	81	-
	PROG		55	55	52	74	R14	82	-
80.	I/O (D7)		56	56	53	75	T16	83	408
81.	GCK3 (I/O)		57	57	54	76	T15	84	411
82.	I/O		-	-	-	77	R13	85	420
83.	I/O		-	-	-	78	P12	86	423
84.	I/O (D6)		58	58	55	79	T14	87	426
85.	I/O		-	59	56	80	T13	88	432
	GND		-	-	-	81	P11	91	-
86.	I/O		-	-	-	82	R11	92	435
87.	I/O		-	-	-	83	T11	93	438
88.	I/O (D5)		59	60	57	84	T10	94	444
89.	I/O ($\overline{CS0}$)		60	61	58	85	P10	95	447
90.	I/O		-	62	59	86	R10	96	450
91.	I/O		-	63	60	87	T9	97	456
92.	I/O (D4)		61	64	61	88	R9	98	459
93.	I/O		62	65	62	89	P9	99	462
	VCC		63	66	63	90	R8	100	-
	GND		64	67	64	91	P8	101	-
94.	I/O (D3)		65	68	65	92	T8	102	468
95.	I/O ($\overline{RS}$)		66	69	66	93	T7	103	471
96.	I/O		-	70	67	94	T6	104	474
97.	I/O		-	-	-	95	R7	105	480
98.	I/O (D2)		67	71	68	96	P7	106	483

Pin	Description	PC84	PQ100	VQ100	TQ144	PQ160	TQ176	PG191	PQ208	Boundary Scan Order
42.	I/O	-	-	-	-	-	28	C11	32	273
43.	I/O	25	19	16	23	25	29	B11	33	279
44.	I/O	26	20	17	24	26	30	A12	34	282
45.	I/O	-	-	-	25	27	31	B12	35	285
46.	I/O	-	-	-	26	28	32	A13	36	291
	GND	-	-	-	27	29	33	C12	37	-
47.	I/O	-	-	-	-	30	34	A15	40	294
48.	I/O	-	-	-	-	31	35	C13	41	297
49.	I/O	27	21	18	28	32	36	B14	42	303
50.	I/O	-	22	19	29	33	37	A16	43	306
51.	I/O	-	-	-	30	34	38	B15	44	309
52.	I/O	-	-	-	31	35	39	C14	45	315
53.	I/O	28	23	20	32	36	40	A17	46	318
54.	I/O	29	24	21	33	37	41	B16	47	321
55.	M1 (I/O)	30	25	22	34	38	42	C15	48	330
	GND	31	26	23	35	39	43	D15	49	-
56.	M0 (I/O)	32	27	24	36	40	44	A18	50	333
	VCC	33	28	25	37	41	45	D16	55	-
57.	M2 (I/O)	34	29	26	38	42	46	C16	56	336
58.	GCK2 (I/O)	35	30	27	39	43	47	B17	57	339
59.	I/O (HDC)	36	31	28	40	44	48	E16	58	348
60.	I/O	-	-	-	41	45	49	C17	59	351
61.	I/O	-	-	-	42	46	50	D17	60	354
62.	I/O	-	32	29	43	47	51	B18	61	360
63.	I/O (LDC)	37	33	30	44	48	52	E17	62	363
64.	I/O	-	-	-	-	49	53	F16	63	372
65.	I/O	-	-	-	-	50	54	C18	64	375
	GND	-	-	-	45	51	55	G16	67	-
66.	I/O	-	-	-	46	52	56	E18	68	378
67.	I/O	-	-	-	47	53	57	F18	69	384
68.	I/O	38	34	31	48	54	58	G17	70	387
69.	I/O	39	35	32	49	55	59	G18	71	390
70.	I/O	-	-	-	-	-	60	H16	72	396
71.	I/O	-	-	-	-	-	61	H17	73	399
72.	I/O	-	36	33	50	56	62	H18	74	402
73.	I/O	-	37	34	51	57	63	J18	75	408
74.	I/O	40	38	35	52	58	64	J17	76	411
75.	I/O ($\overline{\text{ERR}}$, $\overline{\text{INIT}}$)	41	39	36	53	59	65	J16	77	414
	VCC	42	40	37	54	60	66	J15	78	-
	GND	43	41	38	55	61	67	K15	79	-
76.	I/O	44	42	39	56	62	68	K16	80	420
77.	I/O	45	43	40	57	63	69	K17	81	423
78.	I/O	-	44	41	58	64	70	K18	82	426
79.	I/O	-	45	42	59	65	71	L18	83	432
80.	I/O	-	-	-	-	-	72	L17	84	435
81.	I/O	-	-	-	-	-	73	L16	85	438
82.	I/O	46	46	43	60	66	74	M18	86	444
83.	I/O	47	47	44	61	67	75	M17	87	447
84.	I/O	-	-	-	62	68	76	N18	88	450
85.	I/O	-	-	-	63	69	77	P18	89	456
	GND	-	-	-	64	70	78	M16	90	-
86.	I/O	-	-	-	-	71	79	T18	93	459

Pin	Description	PC84	TQ144	PQ160	TQ176	PQ208	PG223	BG225	PQ240	Boundary Scan Order
7.	I/O (A10)	5	133	147	162	190	G1	A6	220	135
8.	I/O (A11)	6	134	148	163	191	G2	B6	221	138
	VCC	-	-	-	-	-	-	VCC*	222	-
9.	I/O	-	-	-	-	-	H4	C6	223	141
10.	I/O	-	-	-	-	-	G4	F7	224	150
11.	I/O	-	135	149	164	192	F1	A5	225	153
12.	I/O	-	136	150	165	193	E1	B5	226	162
	GND	-	137	151	166	194	G3	GND*	227	-
13.	I/O	-	-	-	-	195	F2	D6	228	165
14.	I/O	-	-	-	167	196	D1	C5	229	171
15.	I/O	-	-	152	168	197	C1	A4	230	174
16.	I/O	-	-	153	169	198	E2	E6	231	177
17.	I/O (A12)	7	138	154	170	199	F3	B4	232	183
18.	I/O (A13)	8	139	155	171	200	D2	D5	233	186
19.	I/O	-	-	-	-	-	F4	A3	234	189
20.	I/O	-	-	-	-	-	E4	C4	235	195
21.	I/O	-	140	156	172	201	B1	B3	236	198
22.	I/O	-	141	157	173	202	E3	F6	237	201
23.	I/O (A14)	9	142	158	174	203	C2	A2	238	210
24.	I/O (A15)	10	143	159	175	204	B2	C3	239	213
	VCC	11	144	160	176	205	D3	VCC*	240	-
	GND	12	1	1	1	2	D4	GND*	1	-
25.	GCK1 (A16, I/O)	13	2	2	2	4	C3	D4	2	222
26.	I/O (A17)	14	3	3	3	5	C4	B1	3	225
27.	I/O	-	4	4	4	6	B3	C2	4	231
28.	I/O	-	5	5	5	7	C5	E5	5	234
29.	I/O (TDI)	15	6	6	6	8	A2	D3	6	237
30.	I/O (TCK)	16	7	7	7	9	B4	C1	7	243
31.	I/O	-	-	8	8	10	C6	D2	8	246
32.	I/O	-	-	9	9	11	A3	G6	9	249
33.	I/O	-	-	-	-	12	B5	E4	10	255
34.	I/O	-	-	-	-	13	B6	D1	11	258
35.	I/O	-	-	-	-	-	D5	E3	12	261
36.	I/O	-	-	-	-	-	D6	E2	13	267
	GND	-	8	10	10	14	C7	GND*	14	-
37.	I/O	-	9	11	11	15	A4	F5	15	270
38.	I/O	-	10	12	12	16	A5	E1	16	273
39.	I/O (TMS)	17	11	13	13	17	B7	F4	17	279
40.	I/O	18	12	14	14	18	A6	F3	18	282
	VCC	-	-	-	-	-	-	VCC*	19	-
41.	I/O	-	-	-	-	-	D7	F2	20	285
42.	I/O	-	-	-	-	-	D8	F1	21	291
43.	I/O	-	-	-	15	19	C8	G4	23	294
44.	I/O	-	-	-	16	20	A7	G3	24	297
45.	I/O	-	13	15	17	21	B8	G2	25	306
46.	I/O	-	14	16	18	22	A8	G1	26	309
47.	I/O	19	15	17	19	23	B9	G5	27	318
48.	I/O	20	16	18	20	24	C9	H3	28	321
	GND	21	17	19	21	25	D9	GND*	29	-
	VCC	22	18	20	22	26	D10	VCC*	30	-
49.	I/O	23	19	21	23	27	C10	H4	31	327

Pin	Description	PQ160	HQ208	HQ240	PG299	BG225	BG352	Boundary Scan Order
100.	I/O	-	-	-	F17	-	AE22	558
101.	I/O	-	-	-	G16	-	AF23	564
102.	I/O	49	63	69	D19	K7	AD20	567
103.	I/O	50	64	70	E18	M5	AE21	570
104.	I/O	-	65	71	D20	R4	AF21	576
105.	I/O	-	66	72	G17	N5	AC19	579
106.	I/O	-	-	73	F18	P5	AD19	582
107.	I/O	-	-	74	H16	L6	AE20	588
108.	I/O	-	-	-	E19	-	AF20	591
109.	I/O	-	-	-	F19	-	AC18	594
	GND	51	67	75	E20	GND*	GND*	-
110.	I/O	52	68	76	H17	R5	AD18	600
111.	I/O	53	69	77	G18	M6	AE19	603
112.	I/O	54	70	78	G19	N6	AC17	606
113.	I/O	55	71	79	H18	P6	AD17	612
	VCC	-	-	80	F20	VCC*	VCC*	-
114.	I/O	-	72	81	J16	R6	AE17	615
115.	I/O	-	73	82	G20	M7	AE16	618
116.	I/O	-	-	-	H20	-	AF16	624
117.	I/O	-	-	-	J18	-	AC15	627
118.	I/O	-	-	84	J19	N7	AD15	630
119.	I/O	-	-	85	K16	P7	AE15	636
120.	I/O	56	74	86	J20	R7	AF15	639
121.	I/O	57	75	87	K17	L7	AD14	642
122.	I/O	58	76	88	K18	N8	AE14	648
123.	I/O ($\overline{\text{ERR}}$, $\overline{\text{INIT}}$)	59	77	89	K19	P8	AF14	651
	VCC	60	78	90	L20	VCC*	VCC*	-
	GND	61	79	91	K20	GND*	GND*	-
124.	I/O	62	80	92	L19	L8	AE13	660
125.	I/O	63	81	93	L18	P9	AC13	663
126.	I/O	64	82	94	L16	R9	AD13	672
127.	I/O	65	83	95	L17	N9	AF12	675
128.	I/O	-	84	96	M20	M9	AE12	678
129.	I/O	-	85	97	M19	L9	AD12	684
130.	I/O	-	-	-	N20	-	AC12	687
131.	I/O	-	-	-	M18	-	AF11	690
132.	I/O	-	-	99	N19	R10	AE11	696
133.	I/O	-	-	100	P20	P10	AD11	699
	VCC	-	-	101	T20	VCC*	VCC*	-
134.	I/O	66	86	102	N18	N10	AE9	702
135.	I/O	67	87	103	P19	K9	AD9	708
136.	I/O	68	88	104	N17	R11	AC10	711
137.	I/O	69	89	105	R19	P11	AF7	714
	GND	70	90	106	R20	GND*	GND*	-
138.	I/O	-	-	-	N16	-	AE8	720
139.	I/O	-	-	-	P18	-	AD8	723
140.	I/O	-	-	107	U20	M10	AC9	726
141.	I/O	-	-	108	P17	N11	AF6	732
142.	I/O	-	91	109	T19	R12	AE7	735
143.	I/O	-	92	110	R18	L10	AD7	738
144.	I/O	71	93	111	P16	P12	AE6	744
145.	I/O	72	94	112	V20	M11	AE5	747

Pin	Description	PQ160	HQ208	HQ240	PG299	BG225	BG352	Boundary Scan Order
146.	I/O	-	-	-	R17	-	AD6	750
147.	I/O	-	-	-	T18	-	AC7	756
148.	I/O	73	95	113	U19	R13	AF4	759
149.	I/O	74	96	114	V19	N12	AF3	768
150.	I/O	75	97	115	R16	P13	AD5	771
151.	I/O	76	98	116	T17	K10	AE3	774
152.	I/O	77	99	117	U18	R14	AD4	780
153.	I/O	78	100	118	X20	N13	AC5	783
	GND	79	101	119	W20	GND*	GND*	-
	DONE	80	103	120	V18	P14	AD3	-
	VCC	81	106	121	X19	VCC*	VCC*	-
	PROG	82	108	122	U17	M12	AC4	-
154.	I/O (D7)	83	109	123	W19	P15	AD2	792
155.	GCK3 (I/O)	84	110	124	W18	N14	AC3	795
156.	I/O	85	111	125	T15	L11	AB4	804
157.	I/O	86	112	126	U16	M13	AD1	807
158.	I/O	-	-	127	V17	N15	AA4	810
159.	I/O	-	-	128	X18	M14	AA3	816
160.	I/O	-	-	-	U15	-	AB2	819
161.	I/O	-	-	-	T14	-	AC1	828
162.	I/O (D6)	87	113	129	W17	J10	Y3	831
163.	I/O	88	114	130	V16	L12	AA2	834
164.	I/O	89	115	131	X17	M15	AA1	840
165.	I/O	90	116	132	U14	L13	W4	843
166.	I/O	-	117	133	V15	L14	W3	846
167.	I/O	-	118	134	T13	K11	Y2	852
168.	I/O	-	-	-	W16	-	Y1	855
169.	I/O	-	-	-	W15	-	V4	858
	GND	91	119	135	X16	GND*	GND*	-
170.	I/O	-	-	136	U13	L15	V3	864
171.	I/O	-	-	137	V14	K12	W2	867
172.	I/O	92	120	138	W14	K13	U4	870
173.	I/O	93	121	139	V13	K14	U3	876
	VCC	-	-	140	X15	VCC*	VCC*	-
174.	I/O (D5)	94	122	141	T12	K15	V2	879
175.	I/O ($\overline{CS0}$)	95	123	142	X14	J12	V1	882
176.	I/O	-	-	-	X13	-	T1	888
177.	I/O	-	-	-	V12	-	R4	891
178.	I/O	-	124	144	W12	J13	R3	894
179.	I/O	-	125	145	T11	J14	R2	900
180.	I/O	96	126	146	X12	J15	R1	903
181.	I/O	97	127	147	U11	J11	P3	906
182.	I/O (D4)	98	128	148	V11	H13	P2	912
183.	I/O	99	129	149	W11	H14	P1	915
	VCC	100	130	150	X10	VCC*	VCC*	-
	GND	101	131	151	X11	GND*	GND*	-
184.	I/O (D3)	102	132	152	W10	H12	N2	924
185.	I/O ($\overline{RS}$)	103	133	153	V10	H11	N4	927
186.	I/O	104	134	154	T10	G14	N3	936
187.	I/O	105	135	155	U10	G15	M1	939
188.	I/O	-	136	156	X9	G13	M2	942
189.	I/O	-	137	157	W9	G12	M3	948

Product Availability

	PINS	64	84	100	100	144	156	160	176	191	208	208	223	225	240	240	299	352
	TYPE	Plast. VQFP	Plast. PLCC	Plast. PQFP	Plast. VQFP	Plast. TQFP	Ceram. PGA	Plast. PQFP	Plast. TQFP	Ceram. PGA	High-Perf. QFP	Plast. PQFP	Ceram. PGA	Plast. BGA	High-Perf. QFP	Plast. PQFP	Ceram. PGA	Plast. BGA
	CODE	VQ64*	PC84	PQ100	VQ100	TQ144	PG156	PQ160	TQ176	PG191	HQ208	PQ208	PG223	BG225	HQ240	PQ240	PG299	BG352
XC5202	-6	CI	CI	CI	CI	CI	CI											
	-5	CI	CI	CI	CI	CI	CI											
	-4	C	C	C	C	C	C											
	-3	C	C	C	C	C	C											
XC5204	-6		CI	CI	CI	CI	CI	CI										
	-5		CI	CI	CI	CI	CI	CI										
	-4		C	C	C	C	C	C										
	-3		C	C	C	C	C	C										
XC5206	-6		CI	CI	CI	CI		CI	CI	CI		CI						
	-5		CI	CI	CI	CI		CI	CI	CI		CI						
	-4		C	C	C	C		C	C	C		C						
	-3		C	C	C	C		C	C	C		C						
XC5210	-6		CI			CI		CI	CI			CI	CI	CI		CI		
	-5		CI			CI		CI	CI			CI	CI	CI		CI		
	-4		C			C		C	C			C	C	C		C		
	-3		C			C		C	C			C	C	C		C		
XC5215	-6							CI			CI			CI	CI		CI	CI
	-5							C			C			C	C		C	C
	-4							C			C			C	C		C	C
	-3							C			C			C	C		C	C

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C = Commercial T_J = 0° to +85°C

I= Industrial T_J = -40°C to +100°C

* VQ64 package supports Master Serial, Slave Serial, and Express configuration modes only.

User I/O Per Package

Device	Max I/O	Package Type																
		VQ64	PC84	PQ100	VQ100	TQ144	PG156	PQ160	TQ176	PG191	HQ208	PQ208	PG223	BG225	HQ240	PQ240	PG299	BG352
XC5202	84	52	65	81	81	84	84											
XC5204	124		65	81	81	117	124	124										
XC5206	148		65	81	81	117		133	148	148		148						
XC5210	196		65			117		133	149			164	196	196		196		
XC5215	244							133			164			196	197		244	244

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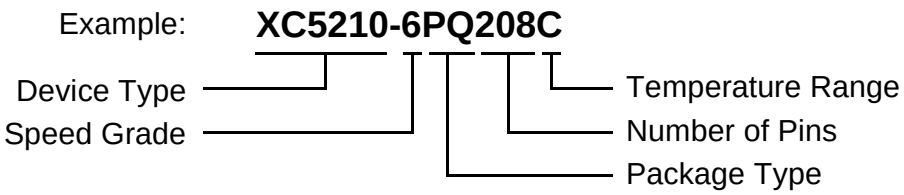
Ordering Information



Revisions

Version	Description
12/97	Rev 5.0 added -3, -4 specification
7/98	Rev 5.1 added Spartan family to comparison, removed HQ304
11/98	Rev 5.2 All specifications made final.